

SQ3000 DD 3D AOI

Automated Optical Inspection



www.nordson.com/TestInspect

Nordson TEST & INSPECTION

Founded in 1954, Nordson Corporation is a market leading industrial technology company with annual revenues of over \$2.1 billion and more than 7,500 employees worldwide.

Nordson TEST & INSPECTION offers its SMT & Semiconductor customers a robust product portfolio, including Acoustic, Optical and both Manual and Automated X-ray Inspection systems, X-ray Component Counting systems and Semiconductor measurement sensors. Nordson TEST & INSPECTION is uniquely positioned to serve its customers with best-in-class precision technologies, passionate sales and support teams, global reach, and unmatched consultative applications expertise.

AOI Products

Proprietary Advanced Technology

> Optical Inspection & Metrology





WS Products

Improve Your

Yields

Semiconductor

Metrology Sensors

Qualify Your Design

Acoustic Inspection





BT Products Test Your Design

Bondtesters





AXI Products

High Speed High Flexibility

Automated X-ray Inspection





MXI Products

Making the Invisible, Visible

> Manual X-ray Inspection









Measuring the Invisible

Automated X-ray Metrology





CC Products

Maximize Efficiency

X-ray Component Counting





XRT Products

High Speed High Resolution

X-ray Technologies



The Ultimate in Speed & Accuracy

Powered by 2 MRS[®] Sensors

SQ3000 DD is The Ultimate in Speed and Accuracy Dual Lane - Dual Sensor Inspection System, powered by 2 MRS[®] Sensors.



Multi-Reflection Suppression® (MRS®) Technology

The SQ3000 DD is powered by Nordson TEST & INSPECTION's breakthrough 3D sensing technology comprising of two MRS Sensors delivering metrology grade accuracy at production speed. Nordsons' unique sensor architecture simultaneously captures and transmits multiple images in parallel while proprietary 3D fusing algorithms merge the images together. The result is ultra-high quality 3D images and high-speed inspection. The SQ3000 D (dual lane, single sensor) is also available.

Flexibility At Its Best

The SQ3000 DD 3D Automated Optical Inspection (AOI) System is an extension of the award-winning SQ3000 3D AOI platform. The dual lane, dual sensor system maximizes flexibility catering to varying PCB widths. This unique design provides the ability to inspect high volume assemblies, the convenience of inspecting different assemblies and board sizes simultaneously on different lanes, or even switching from dual lane to single lane mode to inspect very large boards.

Not only does the SQ3000 DD provide PCB flexibility, it also provides the flexibility to choose two of the same or two different proprietary MRS sensors.



Shorter Inspection Times



Versatility for Applications with High Quality Requirements

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Multi-Reflection Suppression®

(MRS[®]) Sensor Technology

The SQ3000 DD offers unmatched accuracy with the revolutionary Multi-Reflection Suppression[®] (MRS[®]) technology by meticulously identifying and rejecting reflections caused by shiny components.

Reflection based distortions

MRS is designed to Inhibit reflection-based distortions from shiny and specular surfaces.





Enabling the highest possible inspection accuracy at production speeds.



Nordsons' unique sensor architecture simultaneously captures and transmits multiple images in parallel while proprietary 3D fusing algorithms merge the images together. The result is ultra-high quality 3D images, accurate to sub 10 µm at production speed.

MULTIP Standard **MRS Sensor**

The Ultra-High Resolution MRS sensor enhances the SQ3000 platform, delivering superior inspection performance, ideally suited for the 0201 metric process and micro-electronic applications where an even greater degree of accuracy and inspection reliability is critical



Nordson's MRS Sensor for SQ3000 DD 3D AOI, SPI and CMM' breakthrough 3D sensing technology comprising four multi-view 3D sensors and a parallel projector delivering metrology grade accuracy at production speed.

LE MRS S	ENSOR OPTION	IS
High	High	Ultra High
peed	Resolution	Resolution

Enable Smarter, Faster Inspection

Faster, Highly Accurate CMM Suite

The multi-award winning SQ3000 AOI software is a more powerful yet extremely simple software suite designed with an intuitive interface and multi-touch control with 3D image visualization tools.

Ultra-fast programming capabilities

Bring the ease-of-use to a completely new level and significantly speed setup, simplifie the process, reduce training efforts and minimize operator interaction – all saving time and cost.

Enable smarter, faster inspection

Speed programming and tuning with new capabilities including AutoTeach, AutoTune and AutoDefine for faster set-up and simplify process.

Al²

Al² (Autonomous Image Interpretation) technology is all about keeping it simple - no parameters to adjust or algorithms to tune. And, you don't need to anticipate defects or pre-define variance either - Al² does it all for you. With Al², you have the power to inspect the most comprehensive list of features and identify the widest variety of defects. Al² offers precise discrimination with just one panel inspection making it a perfect solution for high-mix and high-volume applications.





Failed Model



Passed Model

Nordson Software Solution provides our customers and partners the best added-value possible for inspection and measurement in electronics manufacturing.

CyberCMM software suite

CyberCMM[™], a comprehensive software suite of coordinate measurement tools, provides highly accurate, 100% metrology-grade measurement on all critical points much faster than a traditional CMM, including coplanarity, distance, height and datum X, Y to name a few. A fast and easy set-up can be performed with the world's first in-line CMM system for programming complex applications as compared to slow, engineering resource-intensive set-ups that typically requires multiple adjustments with traditional coordinate measurement machines (CMMs).

Fast, scalable SPC solution

CyberReport[™] offers full-fledged machine to factory level SPC capability with powerful historical analysis and reporting tools. The software delivers complete traceability for effective process verification and yield improvement.

CyberReport is designed for simple set-up and intuitive use, while simultaneously delivering scalability, fast charting, and an extremely compact database size.



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Measure critical points faster than traditional measurement systems.



High End Applications

The SQ3000-DD offers unmatched accuracy with the revolutionary Multi-Reflection Suppression (MRS) technology. Effective suppression of multiple reflections is critical for accurate measurement, making MRS an ideal technology solution for a wide range of applications including those with very high quality requirements.



Advanced Packaging

Fine pitch component inspection. BGA solder ball inspection, diameter measurement, uniformity. BGA coplanarity inspection.

LED

Backlight. Five point & solder paste inspection. Pad Gap inspection. Warpage corpenarity, Illumination Intensity & Adhesive Squeeze out measurements. Dye chip out.



Advanced Socket Metrology

Pin inspection, True position, Inspection on dispensed material, Inspecting dispensed patterns.



Tight area, Off water bridging, Speed and accuracy, Jet print paste, Type 4 paste.





Highly reflective dye, Wirebond, Ribbons, Ball bond, Wirebonding and wedgebond inspection, Wirebond loop height of wire bond, Cornerfill/Underfill inspection.





Tighter tolerance, Higher demand for accuracy, Small components, More micro electronics, Conformal coating, Life Critical.

Defense

Component Verification, Counterfeit part detection, High map & Point cloud output capabilities, Adhesive & epoxy inspection.



Metal modules that have cavities, Suberate & Critical inspection on highly reflective material, Wire bond and ribbon inspection.



Tuning forks, connector, True position for key features, True position for key component for high precision placement, Smaller Modules, Critical pin inspection

Fast programming, Speed and Accuracy, Quick programming.











Specifications

Inspection Capabilities	Standard MRS Sensor	High-Speed MRS Sensor	High-Resolution MRS Sensor	Ultra-High Resolution MRS Sensor				
Inspection Speed	40 cm²/sec (2D+3D)	50 cm²/sec (2D+3D)	20 cm ² /sec (2D+3D)	15 cm²/sec (2D+3D)				
Minimum Component Size	0402 mm (0	01005 in.)	0201 mm (0	08004 in.)				
PCB Size	SQ3000 DD: Single Lane: 510 x 510 mm (20 x 20 in.); Dual Lane: 350 x 320 mm (13.7 x 12.5in.) SQ3000 D: Single Lane: 510 x 510 mm (20 x 20 in.); Dual Lane: 510 x 320 mm (20 x 12.5 in.)							
Component Height Clearance	Top: 50 mm ; Bottom: 30mm							
PCB Thickness	0.3 - 5 mm							
Component Types Inspected	Standard SMT (chips, J-lead, gull-wing, BGA, etc.), through-hole, odd-form, clips, connectors, header pins, and more							
Component Defects	Missing, polarity, tombstone, billboard, flipped, wrong part, gross body and lead damage, and more							
Solder Joint and Other Defects	Gold finger contamination, excess solder, insufficient solder, bridging, through-hole pins							
3D Measurement Inspection	Lifted Lead, package coplanarity, polarity dimple and chamfer identification							
Measurement Gage R&R	<10% @ ±3σ (±80 μm process tolerance)							
Z Height Accuracy	1 μm on certification target							
Z Measurement Range	6 mm at spec, 24	mm capability	3 mm at spec, 8 mm capability					
Vision System & Technology								
Imagers		Multi-3D	sensors					
Imagers Resolution	Sub 1	Multi-3D 0 μm	sensors 7 µ	ım				
Imagers Resolution Field of View (FOV)	Sub 1 36 x 30 mm	Multi-3D 0 μm 36 x 36 mm	sensors 7 µ 26 x 26 mm	1m 21 x 21 mm				
Imagers Resolution Field of View (FOV) Image Processing	Sub 1 36 x 30 mm Autonomou	Multi-3D 0 μm 36 x 36 mm s Image Interpretation (AI²) Tech	sensors 7 µ 26 x 26 mm nology, Coplanarity and Lead M	ım 21 x 21 mm easurement				
Imagers Resolution Field of View (FOV) Image Processing Programming Time	Sub 1 36 x 30 mm Autonomou	Multi-3D 0 μm 36 x 36 mm s Image Interpretation (AI ²) Tech <13 minutes (for es	sensors 7 µ 26 x 26 mm nology, Coplanarity and Lead M tablished libraries)	um 21 x 21 mm easurement				
Imagers Resolution Field of View (FOV) Image Processing Programming Time CAD Import	Sub 1 36 x 30 mm Autonomou Any column-sepa	Multi-3D 0 μm 36 x 36 mm s Image Interpretation (AI ²) Tech <13 minutes (for es rated text file with ref designator	sensors 7 µ 26 x 26 mm nology, Coplanarity and Lead M tablished libraries) ; XY, Angle, Part no info; Valor pro	IM 21 x 21 mm easurement press preparation				
Imagers Resolution Field of View (FOV) Image Processing Programming Time CAD Import	Sub 1 36 x 30 mm Autonomou Any column-sepa	Multi-3D .0 μm 36 x 36 mm s Image Interpretation (AI ²) Tech <13 minutes (for es rated text file with ref designator	sensors 7 µ 26 x 26 mm nology, Coplanarity and Lead M tablished libraries) , XY, Angle, Part no info; Valor pro	um 21 x 21 mm easurement occess preparation				
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Imagers Resolution Field of View (FOV) Image Processing Programming Time CAD Import System Specifications Machine Interface Power Requirements	Sub 1 36 x 30 mm Autonomou Any column-sepa	Multi-3D 0 μm 36 x 36 mm s Image Interpretation (AI ²) Tech <13 minutes (for es rated text file with ref designator SMEMA, RS232 100-120 VAC or 220-240 V	sensors 7 µ 26 x 26 mm nology, Coplanarity and Lead M tablished libraries) ; XY, Angle, Part no info; Valor pro 2 and Ethernet AC, 50/60 hz, 10-15 amps	Im 21 x 21 mm easurement occess preparation				
Imagers Resolution Field of View (FOV) Image Processing Programming Time CAD Import System Specifications Machine Interface Power Requirements Compressed Air Requirements	Sub 1 36 x 30 mm Autonomou Any column-sepa	Multi-3D 0 μm 36 x 36 mm s Image Interpretation (AI ²) Tech <13 minutes (for es rated text file with ref designator SMEMA, RS232 100-120 VAC or 220-240 V 5.6 Kgf/cm ² to 7.0 Kgf/cm	sensors 7 µ 26 x 26 mm nology, Coplanarity and Lead M tablished libraries) , XY, Angle, Part no info; Valor pro 2 and Ethernet AC, 50/60 hz, 10-15 amps a ² (80 to 100 psi @ 4 cfm)	Im 21 x 21 mm easurement occess preparation				
Imagers Resolution Field of View (FOV) Image Processing Programming Time CAD Import System Specifications Machine Interface Power Requirements Compressed Air Requirements System Dimensions	Sub 1 36 x 30 mm Autonomou Any column-sepa	Multi-3D 0 μm 36 x 36 mm s Image Interpretation (AI ²) Tech <13 minutes (for es rated text file with ref designator SMEMA, RS232 100-120 VAC or 220-240 V 5.6 Kgf/cm ² to 7.0 Kgf/cm 62 x 152 cm (W x D x H) Height ex	sensors 7 µ 26 x 26 mm nology, Coplanarity and Lead M tablished libraries) , XY, Angle, Part no info; Valor pro 2 and Ethernet AC, 50/60 hz, 10-15 amps 1 ² (80 to 100 psi @ 4 cfm) ccludes signal-light pole and lever	Im 21 x 21 mm easurement occess preparation				
ImagersResolutionField of View (FOV)Image ProcessingProgramming TimeCAD ImportSystem SpecificationsMachine InterfacePower RequirementsCompressed Air RequirementsSystem DimensionsWeight	Sub 1 36 x 30 mm Autonomou Any column-sepa	Multi-3D 0 μm 36 x 36 mm s Image Interpretation (AI ²) Tech <13 minutes (for es arated text file with ref designator SMEMA, RS232 100-120 VAC or 220-240 V 5.6 Kgf/cm ² to 7.0 Kgf/cm 62 x 152 cm (W x D x H) Height es ≈1596 kg (sensors 7 µ 26 x 26 mm nology, Coplanarity and Lead M tablished libraries) ; XY, Angle, Part no info; Valor pro 2 and Ethernet AC, 50/60 hz, 10-15 amps 1 ² (80 to 100 psi @ 4 cfm) ccludes signal-light pole and leve 3519 lbs.)	21 x 21 mm easurement ocess preparation				
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For more information, speak with your Nordson representative or contact your Nordson regional office

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